

Notice of References Cited	Application/Control No. 10/635,649	Applicant(s)/Patent Under Reexamination HATADE ET AL.	
	Examiner VAN T. PHAM	Art Unit 2627	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-7,075,880	07-2006	Honda et al.	369/112.08
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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